

Search Notes

Application/Control No.

10/627,651

Examiner

Nhan T. Tran

Applicant(s)/Patent under
Reexamination

CHANG ET AL.

Art Unit

2622

SEARCHED

Class	Subclass	Date	Examiner
348	335 340 374	6/4/2007	NT
396	535 541	6/5/2007	NT
359	290 224	6/5/2007	NT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST search (USPAT, PGPUB, JPO, EPO, DERWENT, IBM_TDB)	6/4/2007	NT
348/373-376 (text search - see search history printout)	6/4/2007	NT
348/335-344 (text search - see search history printout)	6/4/2007	NT
Inventorship search - see search history printout	6/5/2007	NT